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THIS DRAWING IS AVAILABLE FOR USE BY ALL DEPARTMENTS AND AGENCIES OF THE DEPARTMENT OF DEFENSE				ROVED DiCe					MICROCIRCUIT, LINEAR, HIGH (SOURCE DRIVERS, MONOLITHIC S											
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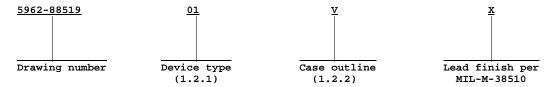
DESC FORM 193

JUL 91

1. SCOPE

1.1 <u>Scope</u>. This drawing describes device requirements for class B microcircuits in accordance with 1.2.1 of MTL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices".

1.2 Part number. The complete part number shall be as shown in the following example:



1.2.1 <u>Device type(s)</u>. The device type(s) shall identify the circuit function as follows:

<u>Device type</u>	Generic number	<u>Circuit function</u>				
01	UDS2981	High current source drivers				
02	UDS2983	High current source drivers				

1.2.2 <u>Case outline(s)</u>. The case outline(s) shall be as designated in appendix C of MIL-M-38510, and as follows:

Outline letter Case outline

D-6 (18-lead, .960" x .310" x .200"), dual-in-line package

1.3 Absolute maximum ratings.

v

1.4 Recommended operating conditions.

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2. APPLICABLE DOCUMENTS

2.1 <u>Government specification and standard</u>. Unless otherwise specified, the following specification and standard of the issue listed in that issue of the Department of Defense Index of Specifications and Standards specified in the solicitation, form a part of this drawing to the extent specified herein.

SPECIFICATION

MILITARY

MIL-M-38510 - Microcircuits, General Specification for.

STANDARD

MILITARY

MIL-STD-883 - Test Methods and Procedures for Microelectronics.

(Copies of the specification and standard required by manufacturers in connection with specific acquisition functions should be obtained from the contracting activity or as directed by the contracting activity.)

2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing shall take precedence.

3. REQUIREMENTS

- 3.1 <u>Item requirements</u>. The individual item requirements shall be in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices" and as specified herein.
- 3.2 <u>Design, construction, and physical dimensions</u>. The design, construction, and physical dimensions shall be as specified in MIL-M-38510 and herein.
 - 3.2.1 Terminal connections. The terminal connections shall be as specified on figure 1.
 - 3.2.2 Test circuit and waveforms. The test circuit and waveforms shall be as specified on figure 2.
 - 3.2.3 Case outline. The case outline shall be in accordance with 1.2.2 herein.
- 3.3 <u>Electrical performance characteristics</u>. Unless otherwise specified herein, the electrical performance characteristics are as specified in table I and apply over the full ambient operating temperature range.
- 3.4 <u>Marking</u>. Marking shall be in accordance with MIL-STD-883 (see 3.1 herein). The part shall be marked with the part number listed in 1.2 herein. In addition, the manufacturer's part number may also be marked as listed in 6.4 herein.
- 3.5 <u>Certificate of compliance</u>. A certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in 6.4. The certificate of compliance submitted to DESC-ECS prior to listing as an approved source of supply shall state that the manufacturer's product meets the requirements of MIL-STD-883 (see 3.1 herein) and the requirements herein.

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Test	Symbol	Conditions <u>1</u> /	Device	Group A	Limits		Unit
		$-55^{\circ}C \le T_{A} \le +125^{\circ}C$ unless otherwise specified	types	subgroups	Min	Max	
Output leakage current	I _{OL}	$v_{S} = 50 \text{ V}, v_{IN} = 0.25 \text{ V}, v_{OUT} = 0 \text{ V} \frac{2}{2}$	01	1,2,3		200	μА
		v _S = 80 v, v _{IN} = 0.25 v, v _{OUT} = 0 v	02	1,2,3		200	
Collector-emmiter saturation voltage	V _{CE} (SAT)	V _{IN} = 2.4 V, I _{OUT} = -350 mA	All	1		2.0	v
		V_{IN} = 2.4 V, I_{OUT} = -100 mA	All 3/	2		1.8	
		V_{IN} = 2.4 V, I_{OUT} = -200 mA				1.9	
		V _{IN} = 2.4 V, I _{OUT} = -100 mA	All	3		2.0	
		V _{IN} = 2.4 V, I _{OUT} = -200 mA		-		2.1	
Input current (outputs open)	I _{IN}	V _{IN} = 2.4 V	All	1,2,3		295	μΑ
		V _{IN} = 3.85 V				600	
		V _{IN} = 12 V				2.3	mA
	I _{IN} (OFF)	v _{IN} = 0 v, v _S = 50 v	01	1,2,3		10	μА
		$V_{IN} = 0 V, V_{S} = 80 V$	02	1,2,3		10	
Output source current (minimum)	I _{OUT}	V _{IN} = 2.4 V, V _{CE} = 2.2 V	All	1,2,3	-200		mA
Supply current (outputs open)	Is	$V_{IN} = 2.4 \text{ V}, V_{S} = 50 \text{ V}, \underline{2}/T_{A} = +25^{\circ}\text{C}$	01	1		10	mA
(Caspada open)		-A . 23 C		2,3		20	1
		$V_{IN} = 2.4 \text{ V}, V_{S} = 80 \text{ V}, \underline{2}/$	02	1		10	1
		T _A = +25°C		2.3		20	

See footnotes at end of table.

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Test	Symbol	Conditions 1/	Device	Group A subgroups	Limits		Unit
	Бушоот	conditions $1/$ -55°C $\leq T_A \leq +125$ °C unless otherwise specified	types		Min	Max	
Turn-on delay	t _{PHL}	V_S = 35 V, R_L = 175 Ω , T_A = +25°C, See figure 2	01	9		2.0	μs
		V_S = 50 V, R_L = 250 Ω , T_A = +25°C, See figure 2	02			2.0	
Turn-off delay	t _{PLH}	$V_S = 35 \text{ V}, R_L = 175\Omega,$ $T_A = +25^{\circ}\text{C},$ See figure 2	01	9		10	
		V_S = 50 V, R_L = 250 Ω , T_A = +25°C, See figure 2	02			10	
Clamp diode leakage current	IR	V _S = V _{OUT} = 50 V, All inputs V _{IN} = 0.25 V	01	1,2,3		50	μА
		V _S = V _{OUT} = 80 V, All inputs V _{IN} = 0.25 V	02	1,2,3		50	
Clamp diode forward voltage	v _F	I _F = 200 mA, V _{IN} = V _S = open	All	1,2,3		1.75	v

 $[\]underline{1}/~\rm V_S$ is 50 V for device type 01 and 80 V for device type 02, unless otherwise specified. $\underline{2}/~\rm All$ inputs simultaneously.

- 3.6 <u>Certificate of conformance</u>. A certificate of conformance as required in MIL-STD-883 (see 3.1 herein) shall be provided with each lot of microcircuits delivered to this drawing.
- ${\tt 3.7} \quad \underline{{\tt Notification \ of \ change}}. \quad {\tt Notification \ of \ change \ to \ DESC-ECS \ shall \ be \ required \ in \ accordance \ with}$ MIL-STD-883 (see 3.1 herein).
- 3.8 <u>Verification and review</u>. DESC, DESC's agent, and the acquiring activity retain the option to review the manufacturer's facility and applicable required documentation. Offshore documentation shall be made available onshore at the option of the reviewer.
- 4. QUALITY ASSURANCE PROVISIONS
- 4.1 Sampling and inspection. Sampling and inspection procedures shall be in accordance with section 4 of MIL-M-38510 to the extent specified in MIL-STD-883 (see 3.1 herein).

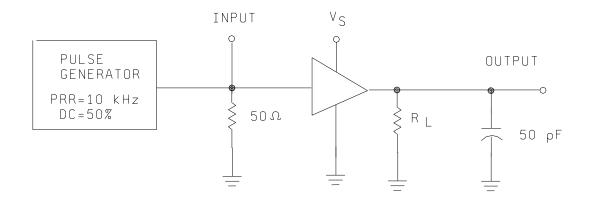
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^{3/} Pulse tested.

Device types	01, 02
Case	v
Terminal number	
1 2 3 4 5 6 7 8 9 10 11 12 13 14 15 16 17	IN 1 IN 2 IN 3 IN 4 IN 5 IN 6 IN 7 IN 8 V _S GND OUT 8 OUT 7 OUT 6 OUT 5 OUT 4 OUT 3 OUT 2
18	OUT 1

FIGURE 1. Terminal connections.

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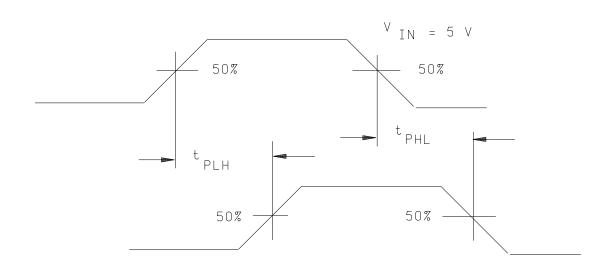


FIGURE 2. Test circuit and waveforms.

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- 4.2 <u>Screening</u>. Screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection. The following additional criteria shall apply:
 - a. Burn-in test, method 1015 of MIL-STD-883.
 - (1) Test condition A, B, C, or D using the circuit submitted with the certificate of compliance (see 3.5 herein).
 - (2) $T_A = +125^{\circ}C$, minimum.
 - b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.
- 4.3 <u>Quality conformance inspection</u>. Quality conformance inspection shall be in accordance with method 5005 of MIL-STD-883 including groups A, B, C, and D inspections. The following additional criteria shall apply.
 - 4.3.1 Group A inspection.
 - a. Tests shall be as specified in table II herein.
 - b. Subgroups 4, 5, 6, 7, 8, 10, and 11 in table I, method 5005 of MIL-STD-883 shall be omitted.
 - 4.3.2 Groups C and D inspections.
 - a. End-point electrical parameters shall be as specified in table II herein.
 - b. Steady-state life test conditions, method 1005 of MIL-STD-883.
 - (1) Test condition A, B, C, or D using the circuit submitted with the certificate of compliance (see 3.5 herein).
 - (2) $T_A = +125^{\circ}C$, minimum.
 - (3) Test duration: 1,000 hours, except as permitted by method 1005 of MIL-STD-883.

TABLE II. <u>Electrical test requirements</u>.

MIL-STD-883 test requirements	Subgroups (per method 5005, table I)
Interim electrical parameters (method 5004)	1
Final electrical test parameters (method 5004)	1*, 2, 3, 9
Group A test requirements (method 5005)	1, 2, 3, 9
Groups C and D end-point electrical parameters (method 5005)	1, 2, 3, 9

* PDA applies to subgroup 1.

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- 5. PACKAGING
- 5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-M-38510.
- 6. NOTES
- 6.1 <u>Intended use</u>. Microcircuits conforming to this drawing are intended for use when military specifications do not exist and qualified military devices that will perform the required function are not available for OEM application. When a military specification exists and the product covered by this drawing has been qualified for listing on QPL-38510, the device specified herein will be inactivated and will not be used for new design. The QPL-38510 product shall be the preferred item for all applications.
- 6.2 <u>Replaceability</u>. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.
- 6.3 <u>Comments</u>. Comments on this drawing should be directed to DESC-ECS, Dayton, Ohio 45444, or telephone 513-296-5377.
- 6.4 Approved source of supply. An approved source of supply are listed herein. Additional sources will be added as they become available. The vendor listed herein has agreed to this drawing and a certificate of compliance (see 3.6 herein) has been submitted to DESC-ECS.

Military drawing part number	Vendor CAGE number	Vendor similar part number <u>1</u> /
5962-8851901VX	56289	UCS-2981/883
5962-8851902VX	56289	UCS-2983/883

1/ <u>Caution</u>. Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.

Vendor CAGE number Vendor name and address

56289

Sprague Electric Company Interface and Linear Integrated Circuits 115 Northeast Cutoff Worcester, MA 01606

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